

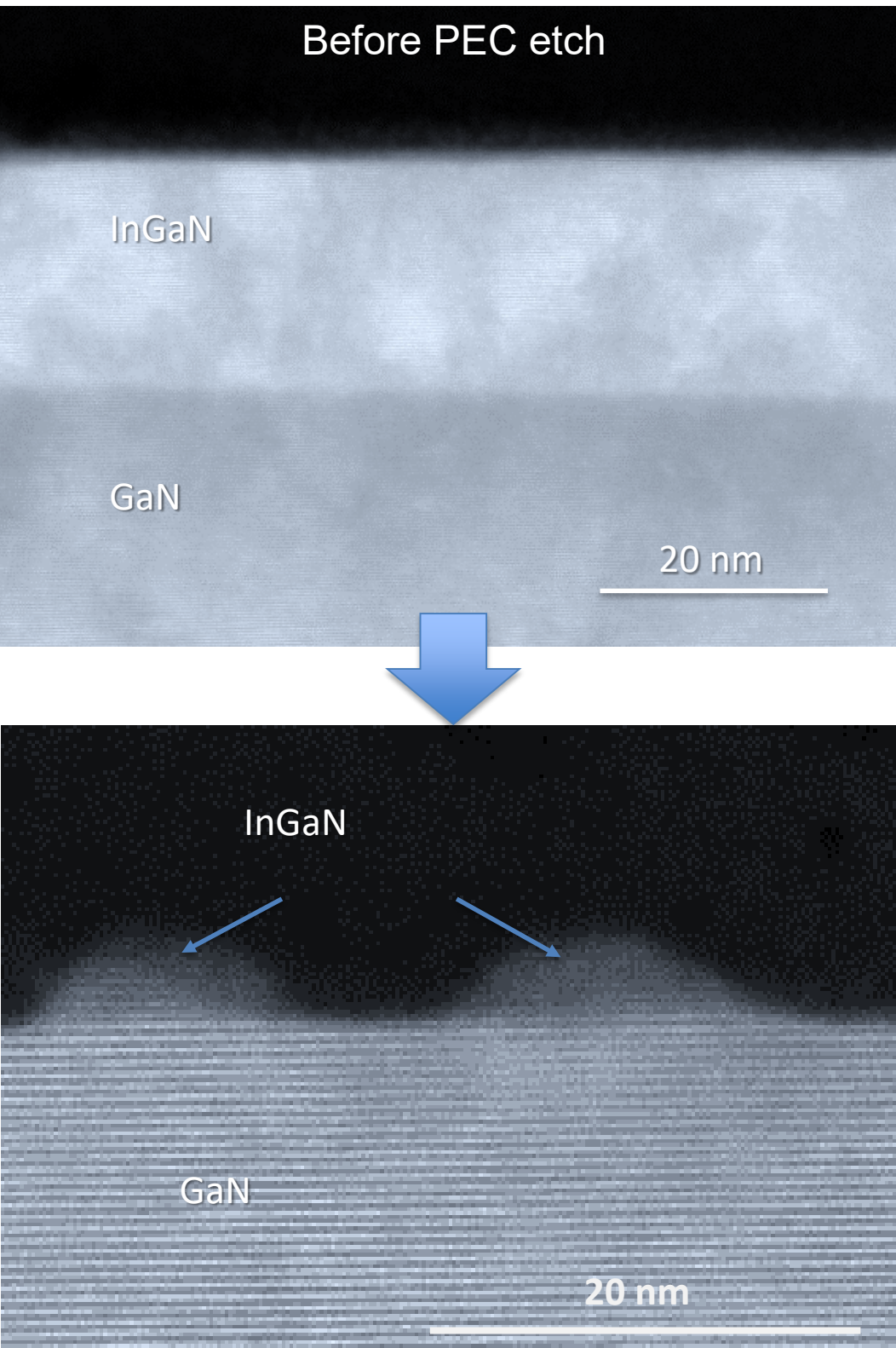
Quantum Size Controlled Etching of InGaN Quantum Dots

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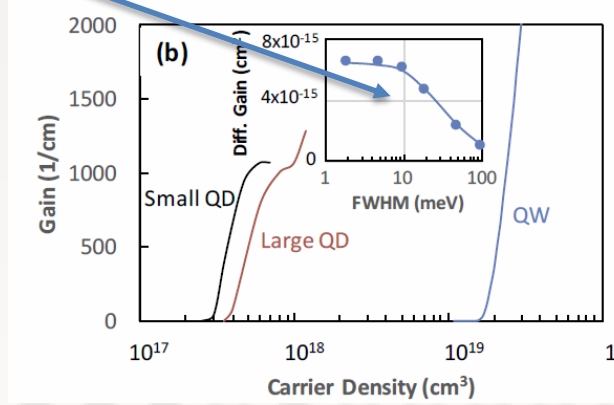


Motivation: InGaN Quantum Dots (QDs) as emitters

Potential advantages vs quantum wells

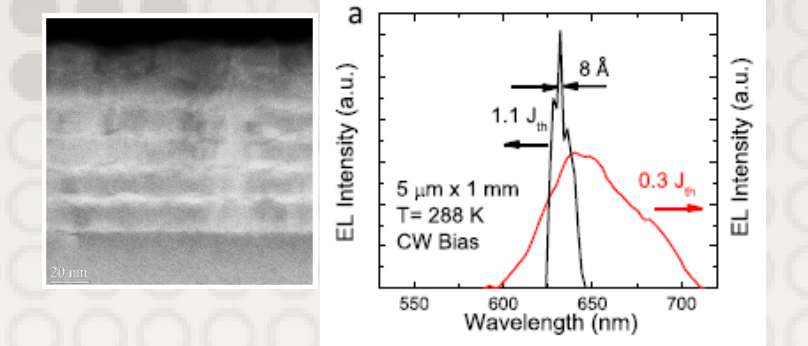
- Single photon emission
- Reduced polarization fields (reduced QCSE)
- Longer wavelength emission
- Lower lasing thresholds
- Higher efficiencies

Quantum nanostructure

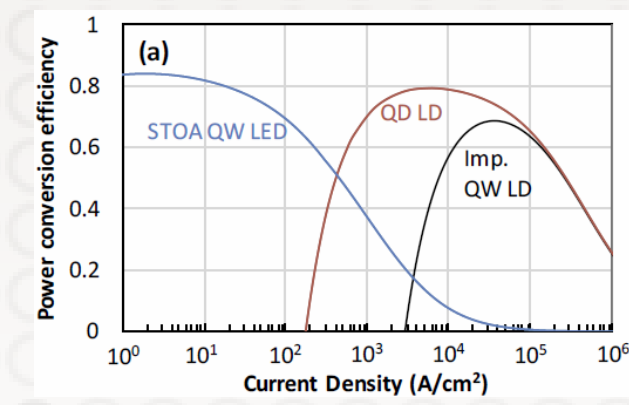


Jonathan J. Wierer, Jr., Nelson Tansu, Arthur J. Fischer, and Jeffrey Tsao, "III-nitride quantum dots for ultra-efficient solid-state lighting," *Laser and Photonics Reviews*, **10**, 612 (2016) / DOI 10.1002/lpor.201500332

U. Mich. - Red electrically injected InGaN QD laser

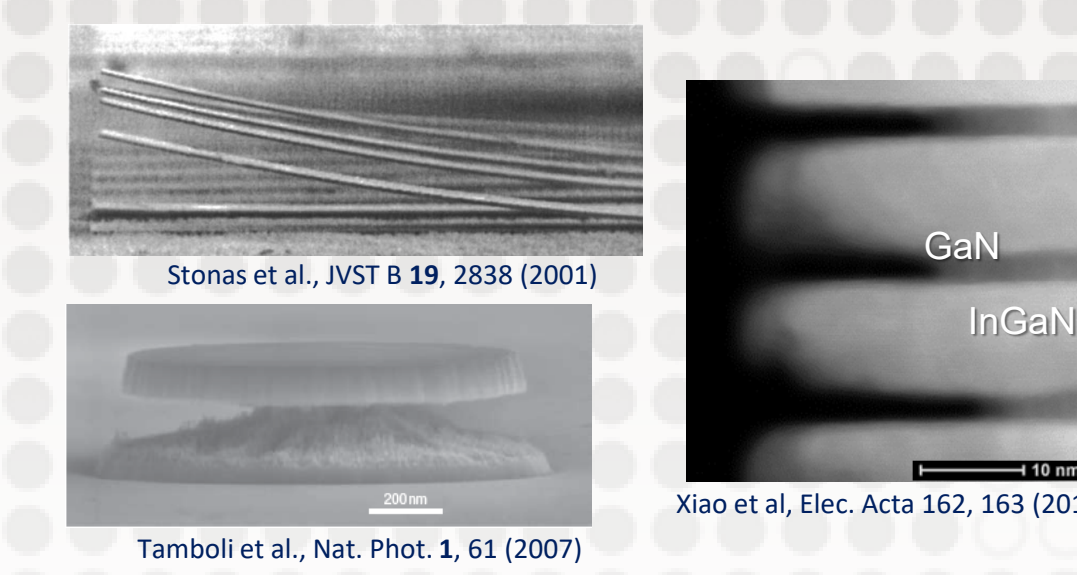
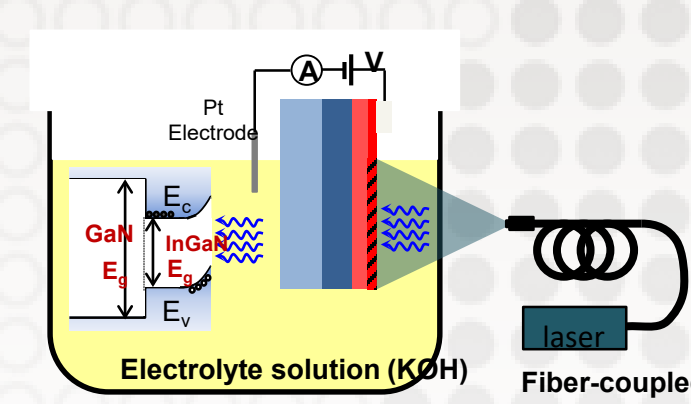


Frost et al., IEEE JQE, **49**, 923 (2013).



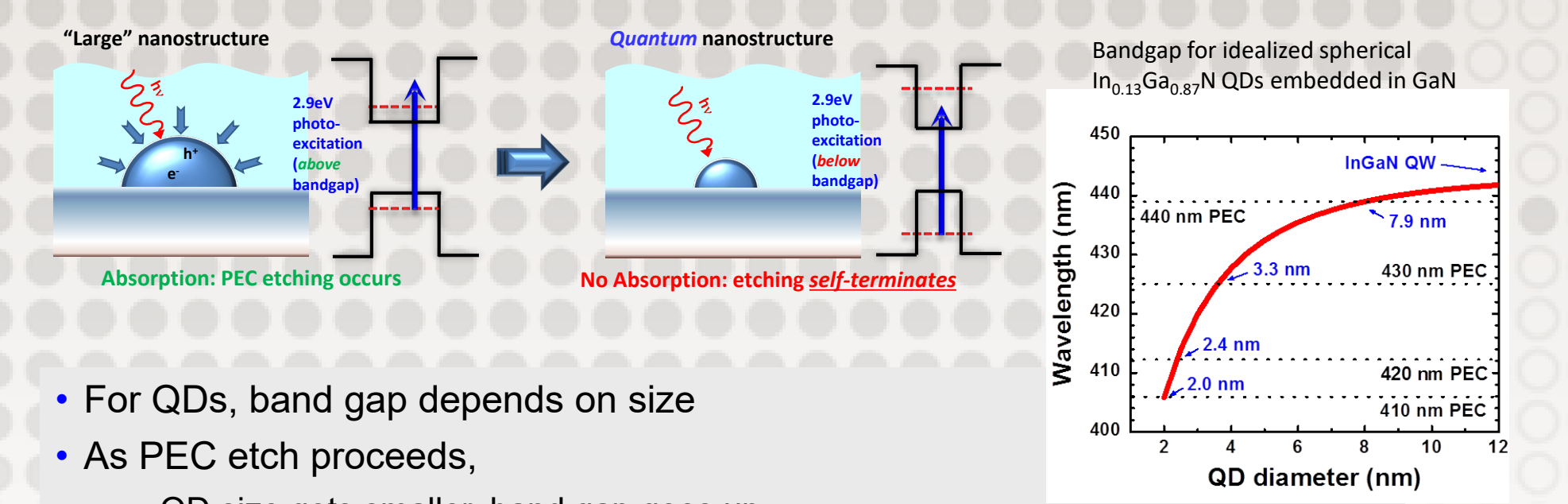
(In)GaN Photoelectrochemical (PEC) Etching

- GaN relatively inert to wet etching, particularly (0001) c-plane
- PEC etching: photogenerated holes oxide surface which is then dissolved
- Laser or lamp excitation (Xe arc lamp, tunable ps Ti:S)
- KOH (~0.1M) typically used as electrolyte for GaN
- Band gap selective (etch InGaN over GaN) based on wavelength used



Quantum-Size Controlled fabrication of QDs

Quantum Size Control: Use size quantization to control QD size



- For QDs, band gap depends on size
- As PEC etch proceeds,
 - QD size gets smaller, band gap goes up
 - Etch should terminate for $E_g > E_{\text{photon pump}}$ (no more carriers needed for etch)
- Self-terminating etch process
- Final QD size (band gap) depends on PEC etch wavelength used
- "Monodisperse" QD distributions ??
- Earlier work on "size selective photocorrosion" to shrink size of colloidal CdS QDs using monochromatic light^{1,2}

Abstract

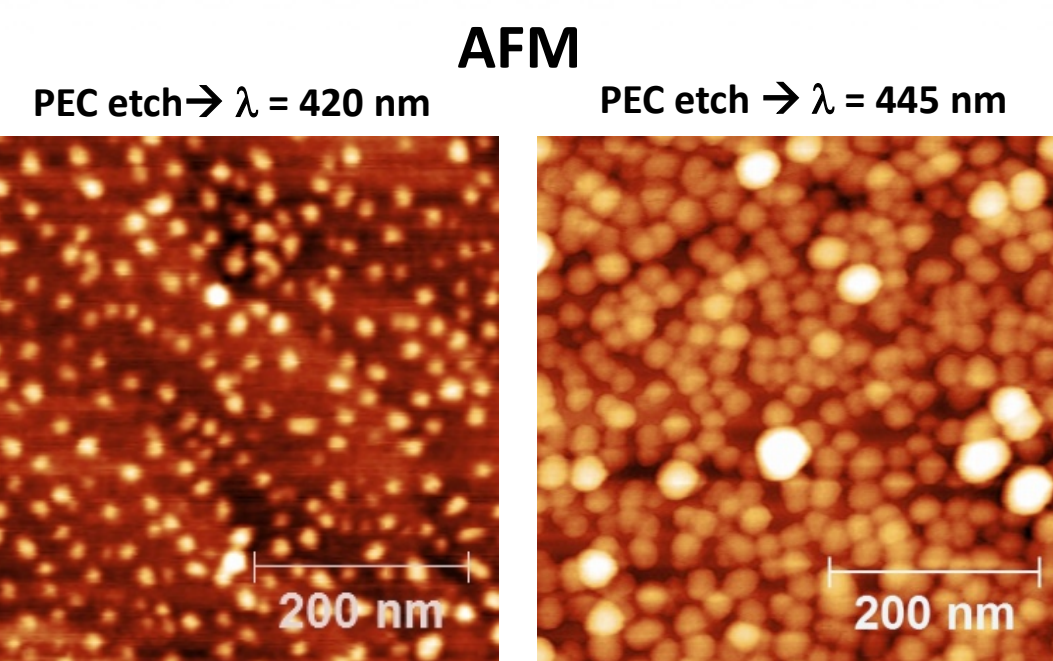
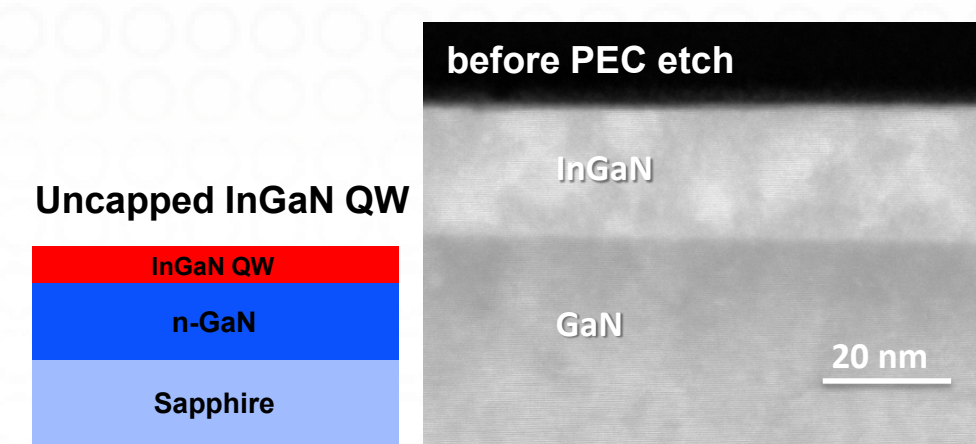
III-nitride quantum dots (QDs) have significant potential for single-photon sources or gain media for low threshold and high efficiency visible and UV lasers, among others. "Bottom-up" Stranski-Krastanov growth is widely used--however both the size distribution and densities are difficult to precisely control. Here, we show a self-terminating top-down fabrication process, called quantum size controlled photo-electrochemical (QSC-PEC) etching, that can be controlled by the evolving properties of the nanostructures being fabricated.

Summary

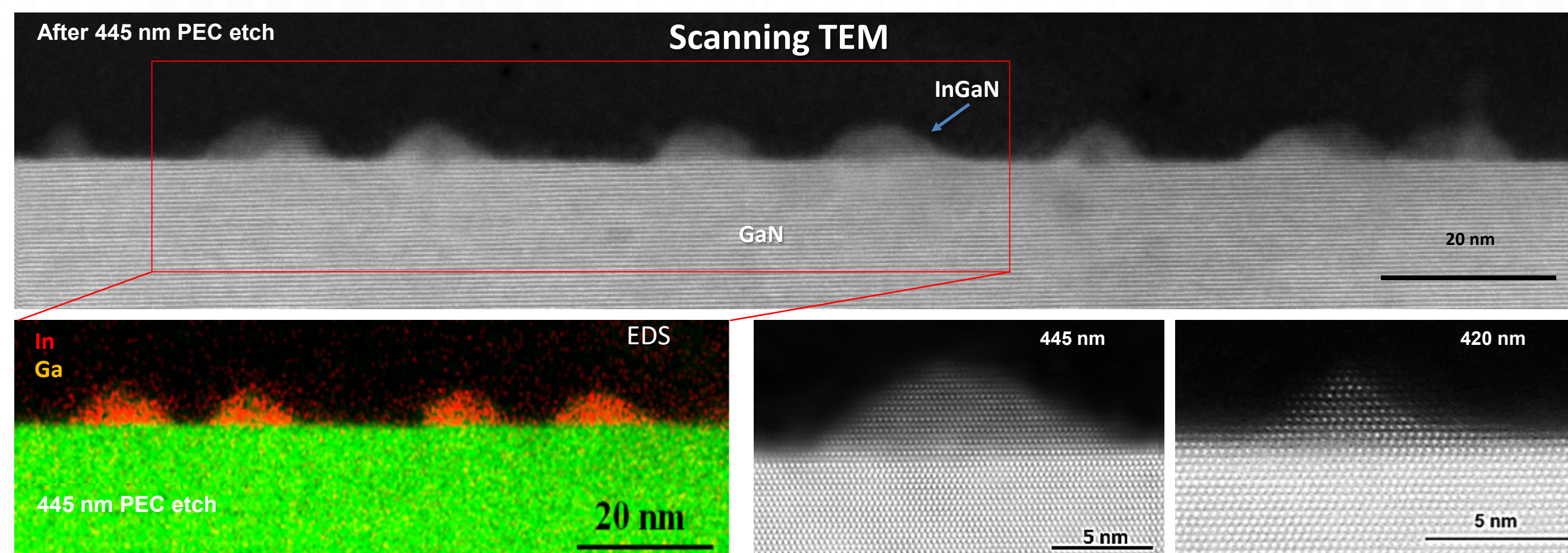
- Demonstrated controlled fabrication of InGaN QDs from epitaxial layer using quantum-size controlled PEC etching
- AFM data indicates extremely high QD density ($\sim 10^{11}$ per cm^2)
- PL linewidth reduced from 24 nm to less than ~ 6 nm, indicating improved QD size distribution vs. Stranski-Krastanov grown InGaN QDs (~ 30 -40 nm)
- PL measurements show significant enhancement of IQE for etched QDs vs initial QW
- QD size and PL emission determined by PEC etch wavelength used!
- Multiple layers of QDs demonstrated, but with lower per-layer density

Uncapped InGaN QW

Uncapped 5 - 20 nm thick $\text{In}_{0.14}\text{Ga}_{0.86}\text{N}$ layer:

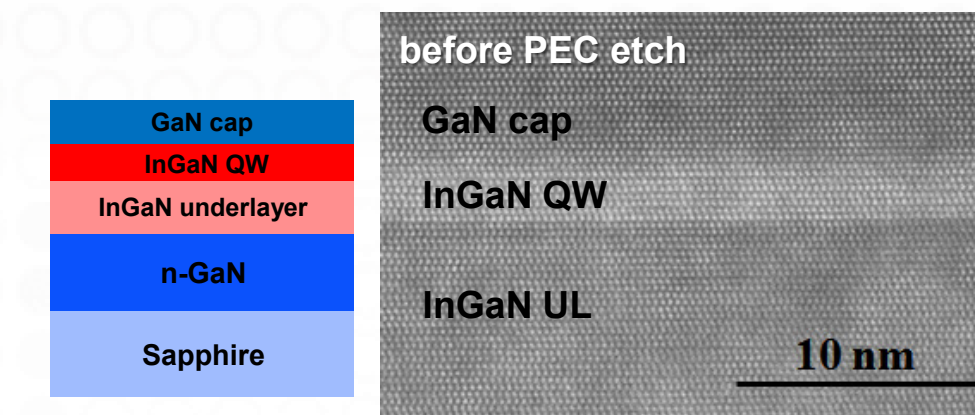


- Samples etched two hours at 420 nm and 445 nm
 - 0.2M H_2SO_4 solution (no dark etch)
 - Tunable Ti:sapphire laser (2 ps pulse width, < 1 nm linewidth, 82 MHz pulse repetition rate), Laser power density: ~ 3 mW/cm²
- Observe formation of (quantum) dots!
 - Very high dot density: $\sim 10^{11}/\text{cm}^2$
- Some big dots (10-20 nm) remain: due to dislocations?
- QD size depends on PEC etch wavelength!

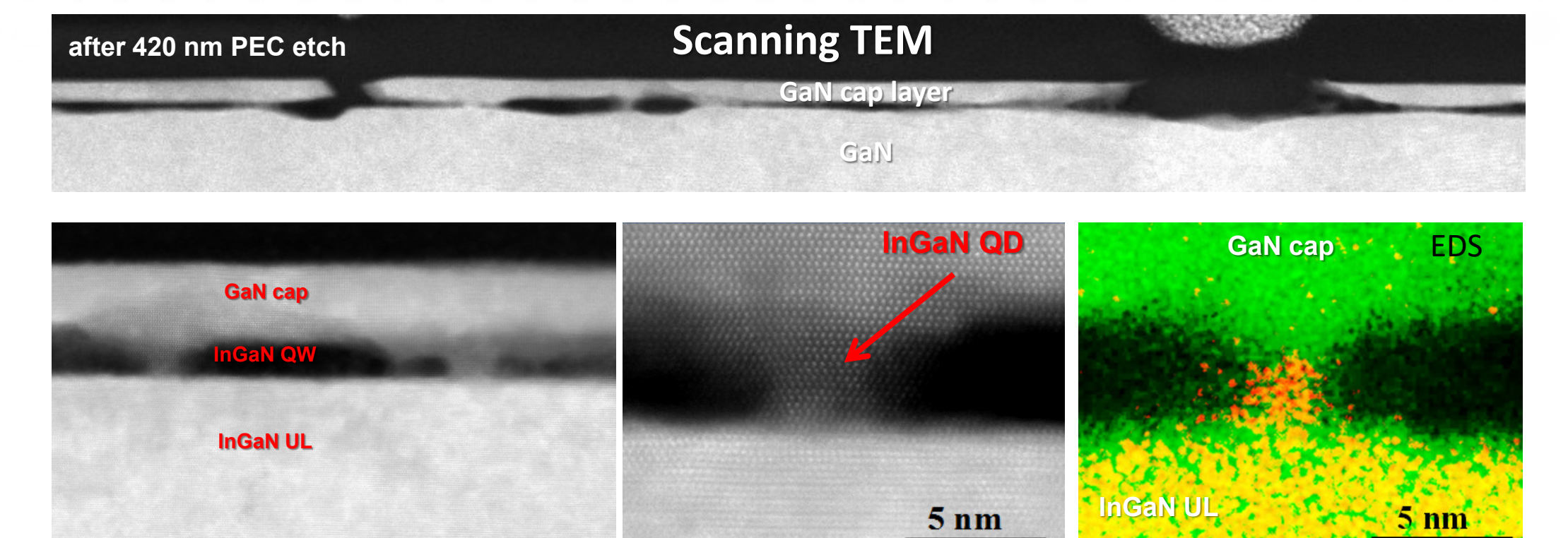


Capped InGaN QW

~ 3 nm $\text{In}_{0.14}\text{Ga}_{0.86}\text{N}$ QW, 10 nm GaN cap

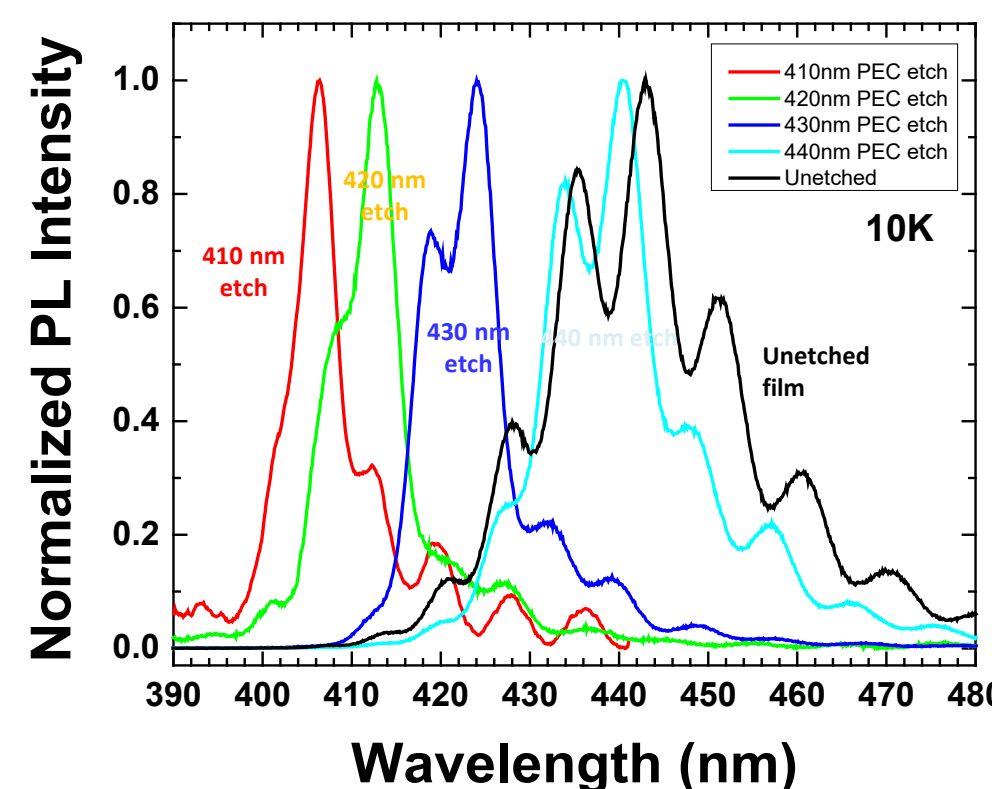


- Sample PEC etched at 420 nm
- Etch appears to break through GaN cap - defects?
- EDS mapping: dots are InGaN
- QD PL is $\sim 100\times$ brighter than uncapped QDs
- GaN cap provides (partial) passivation



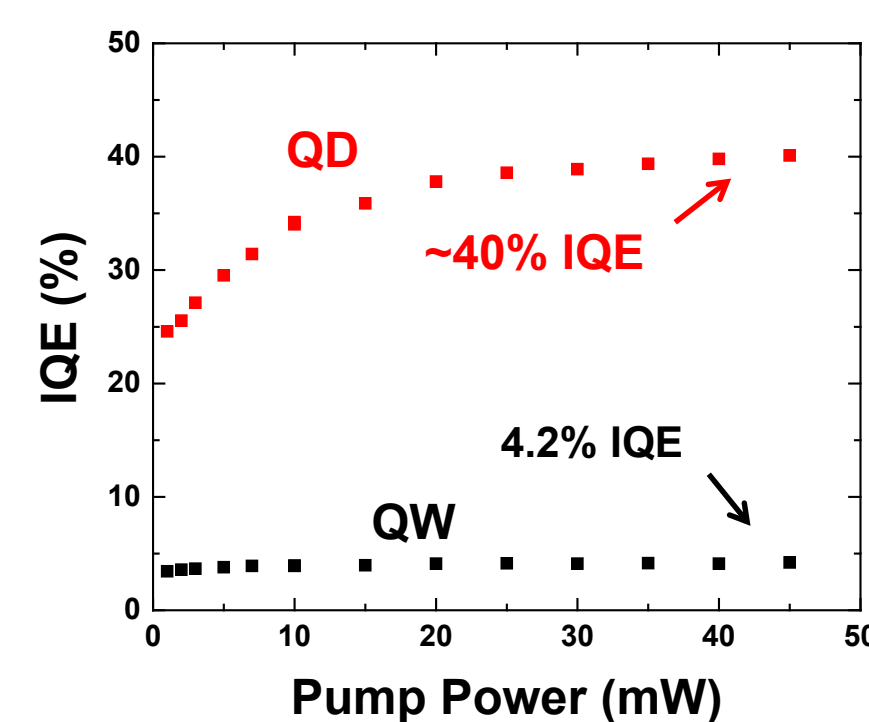
Optical Characterization of QDs

Photoluminescence (PL) of etched QDs



- 375 nm pump (ps pulsed), 10K
- Etched QD PL wavelength correlates (but doesn't exactly coincide) with PEC etch wavelength
- PL linewidth decreases with decreasing etch wavelength: 24 nm (film) $\rightarrow$ 6 nm (QDs etched at 410 nm)
- Strong evidence for quantum-size controlled mechanism!

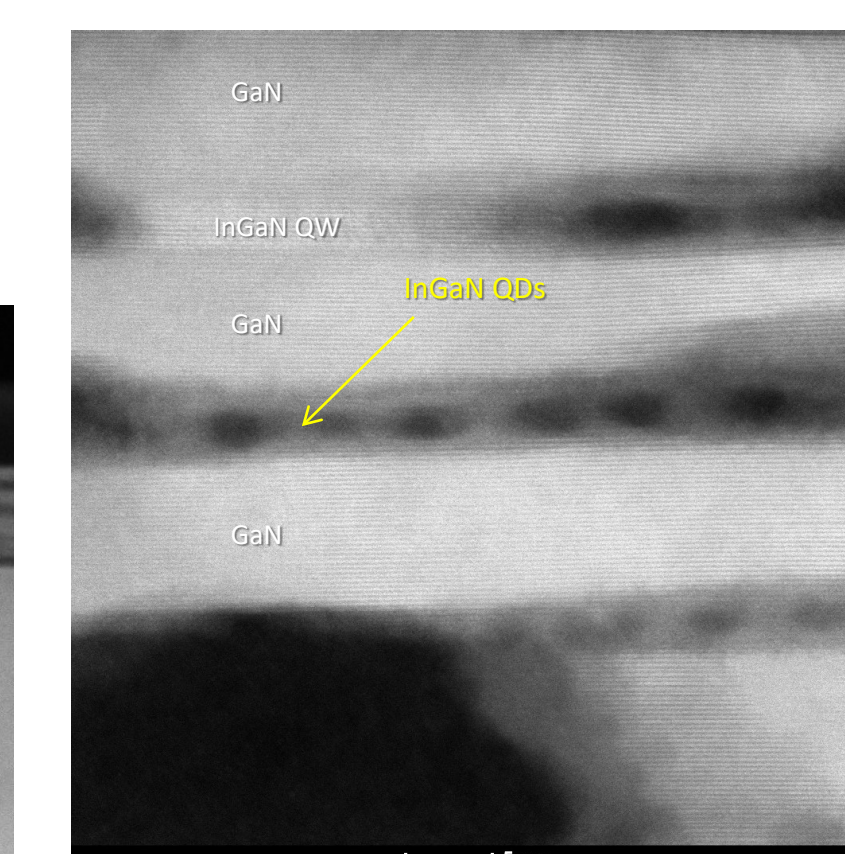
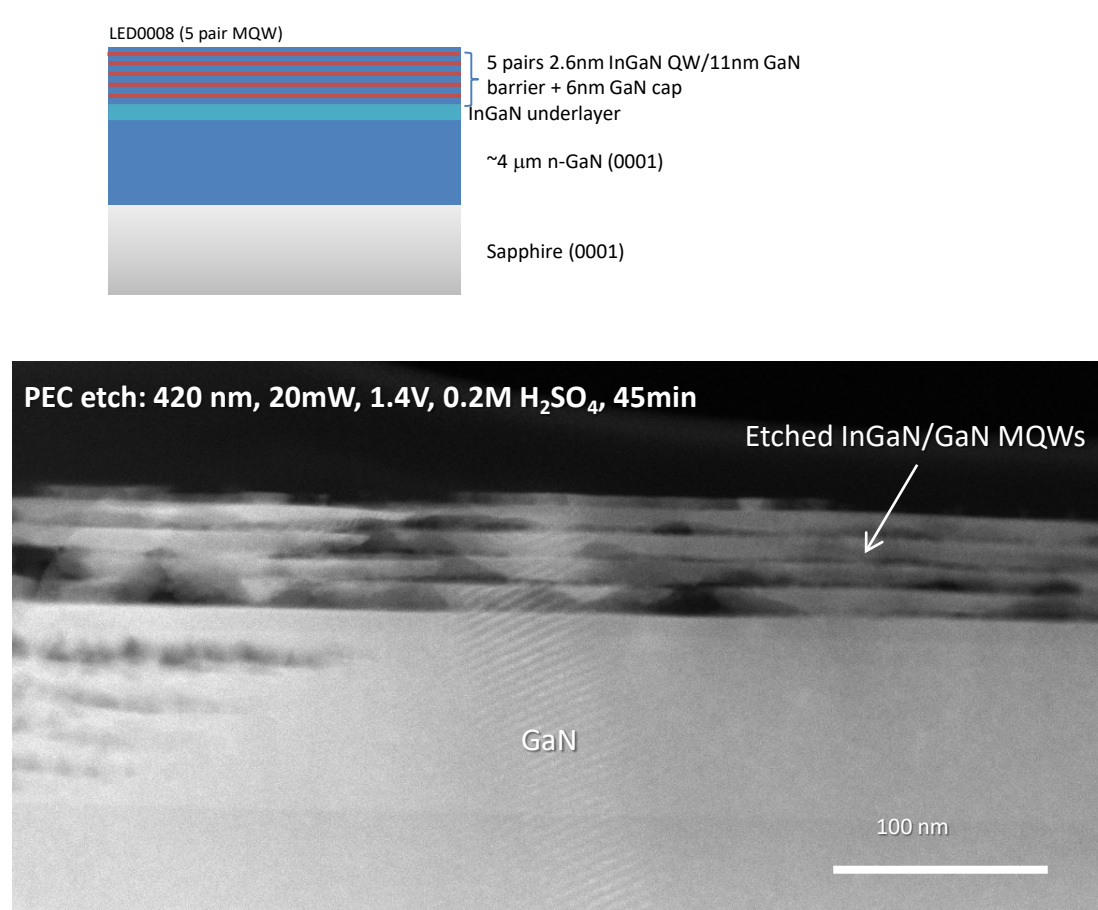
Internal Quantum Efficiency (IQE)



- Compare 10K and RT PL efficiency
- Assumes 10K PL is 100% efficient
- PL Intensity drops by $> 100\times$ after QD etching
- IQE goes up by almost 10X after QD etching

InGaN/GaN Multi-Quantum Wells (MQWs)

- QD lasers need multiple layers of QDs to provide sufficient gain $\rightarrow$ PEC etch InGaN/GaN MQWs to provide multiple layers of capped/passivated QDs?
- Cross-sectional STEM shows all InGaN layers etched after PEC etch at 420 nm, with GaN voids present
- InGaN QD density per layer appears low compared to QSC-PEC etched single InGaN layer, potentially explaining relatively low PL of etched MQW sample



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Acknowledgements

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